Search Notes

Applicant(s)/Patent under Reexamination

09/901,595

Examiner

Jack M. Choules

Reexamination
NAKANO, SHIGERU
Art Unit

2167

SEARCHED				
Class	Subclass	Date	Examiner	
707	10,104.1	12/15/2005	JMC	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
707	10,104	12/15/2005	JMC		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Plus Search East, USPGPUB, USPAT, EPO, JPO, DERWENT, IBM-TDB. Notes in file	12/15/2005	JMC	
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